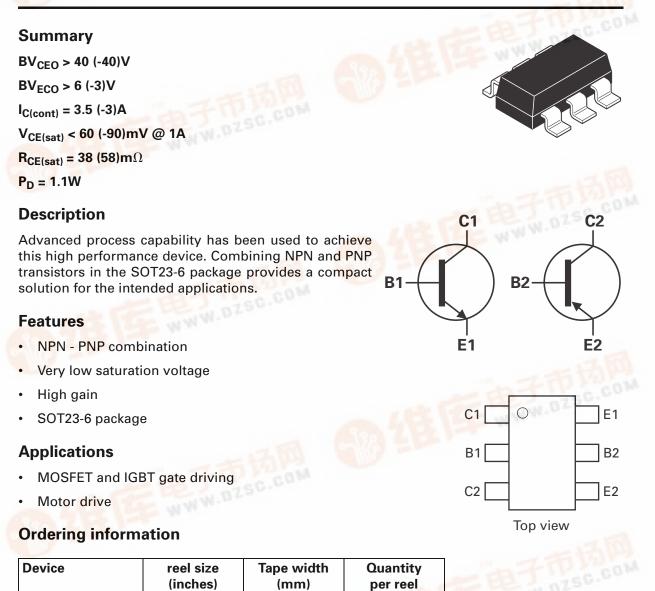


ZXTC2063E6 40V, SOT23-6, complementary medium power transistors



D ·	marking
	marking
DEVICE	Παικιία

7

ZXTC2063E6TA

2063



8

3000

Absolute maximum and thermal ratings

Parameter	Symbol	Limit	Unit
Collector-base voltage	V _{CBO}	130(-45)	V
Collector-emitter voltage	V _{CEO}	40(-40)	V
Emitter-collector voltage (reverse blocking)	V _{ECO}	6(-3)	V
Emitter-base voltage	V _{EBO}	7(-7)	V
Continuous collector current ^{(c)(f)}	۱ _C	3.5(-3)	А
Peak pulse current	I _{CM}	9(-9)	А
Base current	۱ _В	1(-1)	А
Power dissipation @ $T_{amb} = 25^{\circ}C^{(a)(f)}$		0.7	W
Linear derating factor	P _D	5.6	mW/°C
Power dissipation @ $T_{amb} = 25^{\circ}C^{(b)(f)}$		0.9	W
Linear derating factor	PD	7.2	mW/°C
Power dissipation @ $T_{amb} = 25^{\circ}C^{(b)(g)}$		1.1	W
Linear derating factor	PD	8.8	mW/°C
Power dissipation @ $T_{amb} = 25^{\circ}C^{(c)(f)}$		1.1	W
Linear derating factor	PD	8.8	mW/°C
Power dissipation @ $T_{amb} = 25^{\circ}C^{(d)(f)}$		1.7	W
Linear derating factor	PD	13.6	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to +150	°C
Thermal resistance junction to ambient ^{(a)(f)}	R _{⊖JC}	179	°C/W
Thermal resistance junction to ambient ^{(b)(f)}	$R_{\Theta J A}$	139	°C/W
Thermal resistance junction to ambient ^{(b)(g)}	R _{⊕JC}	113	°C/W
Thermal resistance junction to ambient ^{(c)(f)}	$R_{\Theta JC}$	113	°C/W
Thermal resistance junction to ambient ^{(d)(f)}	R _{⊖JA}	73	°C/W

NOTES:

(a) For a device surface mounted on 15mm x 15mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

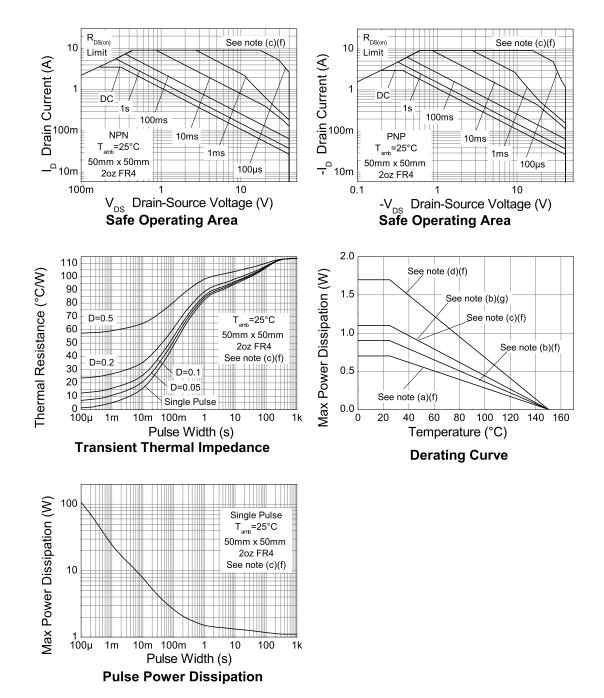
(c) For a device surface mounted on 50mm x 50mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions.

(d) As above measured at t<5 seconds.

(e) Repetitive rating - pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.

(f) For device with one active die, both collectors attached to a common sink.

(g) For device with two active dice running at equal power, split sink 50% to each collector.



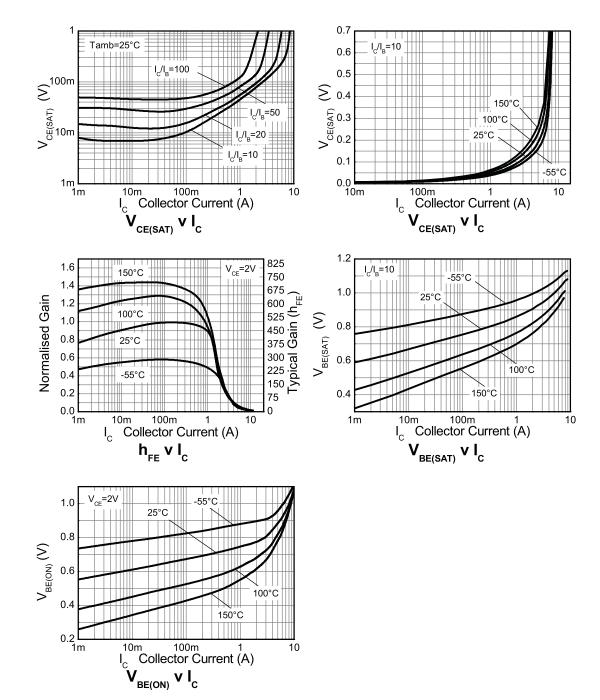
Thermal characteristics

Deveneetev	C. make al	N/1:	T	Mari	11	Conditions
Parameter	Symbol		Тур.	Max.		
Collector-base breakdown voltage	BV _{CBO}	130(-45)	170(-80)		V	I _C = (-)100μA
Collector-emitter breakdown voltage (base open)	BV _{CEO}	(-)40	63(-65)		V	I _C = (-)10mA ^(*) *
Emitter-base breakdown voltage	BV _{EBO}	(-)7	(-)8.3		V	I _E = (-)100μA
Emitter-collector breakdown voltage (reverse blocking)	BV _{ECX}	(-)6	(-)7.4		V	$I_E = (-)100\mu$ A, $R_{BC} < 1k\Omega$ or 0.25V > V_{BC} > -0.25V (0.25V < V_{BC} < -0.25V)
Emitter-collector breakdown voltage (base open)	BV _{ECO}	6(-3)	7.4(-8.7)		V	I _E = (-)100μA
Collector-base cut-off	I _{CBO}		<1	(-)50	nA	V _{CB} =100(-36)V
current				(-)20	μA	V _{CB} =100(-36)V, T _{amb} = 100°C
Emitter-base cut-off current	I _{EBO}		<1	(-)50	nA	V _{EB} = (-)5.6V
Collector-emitter	V _{CE(sat)}		50(-70)	60(-90)	mV	I _C = (-)1A, I _B = (-)100mA *
saturation voltage			85(-195)	110(-290)	mV	I _C = (-)1A, I _B = (-)20mA *
			150	220	mV	I _C = 2A, I _B = 40mA *
			(-175)	(-260)	mV	(I _C = -3A, I _B = -300mA *)
			135	195	mV	I _C = 3.5A, I _B = 350mA *
Base-emitter saturation	$V_{BE(sat)}$		(-935)	(-1000)	mV	(I _C = -3A, I _B = -300mA *)
voltage			960	1050	mV	I _C = 3.5A, I _B = 350mA *
Base-emitter turn-on voltage	V _{BE(on)}		(-855) 860	(-950) 950	mV mV	(I _C = -3A, V _{CE} = -2V *) I _C = 3.5A, V _{CE} = 2V *
Static forward current	h _{FE}	()300	()450	()900		I _C = (-)10mA, V _{CE} = (-)2V *
transfer ratio		280(200)	400(280)			I _C = (-)1A, V _{CE} = (-)2V *
		(20)	(50)			(I _C = -3A, V _{CE} = -2V *)
		40	60			I _C = 3.5A, V _{CE} = 2V *
Transition frequency	f _T		190 (270)		MHz	I _C = (-)50mA, V _{CE} = (-)10V f = 100MHz
Output capacitance	C _{OBO}		12(17)	20(25)	pF	V _{CB} = (-)10V, f = 1MHz *
Delay time	t _d		64(57)		ns	$V_{CC} = (-)10V. I_{C} = (-)1A, I_{B1}$
Rise time	t _r		108(69)		ns	= I _{B2} = (-)10mA.
Storage time	t _s		428(154)		ns	
Fall time	t _f		130(60)		ns	

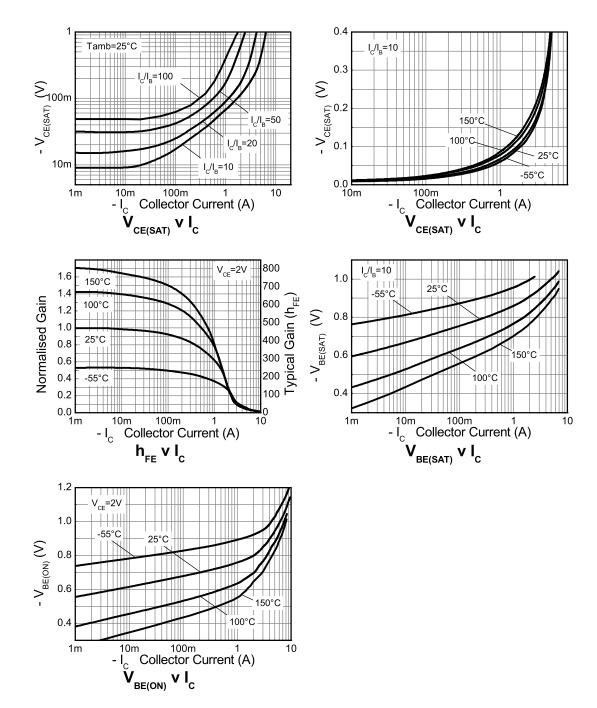
Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

NOTES:

(*) Measured under pulsed conditions. Pulse width ${\leq}300\mu s$; duty cycle ${\leq}2\%$ () = PNP

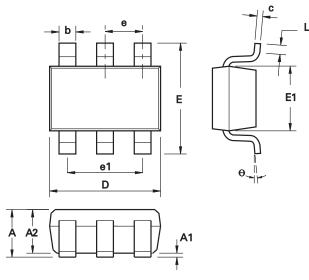


NPN Characteristics



PNP Characteristics

Package outline - SOT23-6



DIM	Millimeters		Inc	hes
	Min.	Max.	Min.	Max.
А	0.90	1.45	0.354	0.0570
A1	0.00	0.15	0.00	0.0059
A2	0.90	1.30	0.0354	0.0511
b	0.35	0.50	0.0078	0.0196
С	0.09	0.26	0.0035	0.0102
D	2.70	3.10	0.1062	0.1220
E	2.20	3.20	0.0866	0.1181
E1	1.30	1.80	0.0511	0.0708
L	0.10	0.60	0.0039	0.0236
е	0.95 REF		0.0374 REF	
e1	1.90	REF	0.074	8 REF
L	0°	30°	0°	30°

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

Definitions

Product change

Zetex Semiconductors reserves the right to alter, without notice, specifications, design, price or conditions of supply of any product or service. Customers are solely responsible for obtaining the latest relevant information before placing orders.

Applications disclaimer

The circuits in this design/application note are offered as design ideas. It is the responsibility of the user to ensure that the circuit is fit for the user's application and meets with the user's requirements. No representation or warranty is given and no liability whatsoever is assumed by Zetex with respect to the accuracy or use of such information, or infringement of patents or other intellectual property rights arising from such use or otherwise. Zetex does not assume any legal responsibility or will not be held legally liable (whether in contract, tort (including negligence), breach of statutory duty, restriction or otherwise) for any damages, loss of profit, business, contract, opportunity or consequential loss in the use of these circuit applications, under any circumstances.

Life support

Zetex products are specifically not authorized for use as critical components in life support devices or systems without the express written approval of the Chief Executive Officer of Zetex Semiconductors plc. As used herein:

A. Life support devices or systems are devices or systems which:

- 1. are intended to implant into the body
- or 2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.
- B. A critical component is any component in a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or to affect its safety or effectiveness.

Reproduction

The product specifications contained in this publication are issued to provide outline information only which (unless agreed by the company in writing) may not be used, applied or reproduced for any purpose or form part of any order or contract or be regarded as a representation relating to the products or services concerned.

Terms and Conditions

All products are sold subjects to Zetex' terms and conditions of sale, and this disclaimer (save in the event of a conflict between the two when the terms of the contract shall prevail) according to region, supplied at the time of order acknowledgement.

For the latest information on technology, delivery terms and conditions and prices, please contact your nearest Zetex sales office.

Quality of product

Zetex is an ISO 9001 and TS16949 certified semiconductor manufacturer.

To ensure quality of service and products we strongly advise the purchase of parts directly from Zetex Semiconductors or one of our regionally authorized distributors. For a complete listing of authorized distributors please visit: www.zetex.com/salesnetwork

Zetex Semiconductors does not warrant or accept any liability whatsoever in respect of any parts purchased through unauthorized sales channels. ESD (Electrostatic discharge)

Semiconductor devices are susceptible to damage by ESD. Suitable precautions should be taken when handling and transporting devices. The possible damage to devices depends on the circumstances of the handling and transporting, and the nature of the device. The extent of damage can vary from immediate functional or parametric malfunction to degradation of function or performance in use over time. Devices suspected of being affected should be replaced.

Green compliance

Zetex Semiconductors is committed to environmental excellence in all aspects of its operations which includes meeting or exceeding regulatory requirements with respect to the use of hazardous substances. Numerous successful programs have been implemented to reduce the use of hazardous substances and/or emissions.

All Zetex components are compliant with the RoHS directive, and through this it is supporting its customers in their compliance with WEEE and ELV directives.

Product status key:			
"Preview"	Future device intended for production at some point. Samples may be available		
"Active"	Product status recommended for new designs		
"Last time buy (LTB)"	Device will be discontinued and last time buy period and delivery is in effect		
"Not recommended for new designs"	Device is still in production to support existing designs and production		
"Obsolete"	Production has been discontinued		
Datasheet status key:			
"Draft version"	This term denotes a very early datasheet version and contains highly provisional information, which may change in any manner without notice.		
"Provisional version"	This term denotes a pre-release datasheet. It provides a clear indication of anticipated performance However, changes to the test conditions and specifications may occur, at any time and without notice.		
"Issue"	This term denotes an issued datasheet containing finalized specifications. However, changes to specifications may occur, at any time and without notice.		

Zetex sales offices

Europe	Americas	Asia Pacific	Corporate Headquarters
Zetex GmbH	Zetex Inc	Zetex (Asia Ltd)	Zetex Semiconductors plc
Kustermann-park	700 Veterans Memorial Highway	3701-04 Metroplaza Tower 1	Zetex Technology Park, Chadderton
Balanstraße 59	Hauppauge, NY 11788	Hing Fong Road, Kwai Fong	Oldham, OL9 9LL
D-81541 München	USA	Hong Kong	United Kingdom
Germany Telefon: (49) 89 45 49 49 0	Telephone: (1) 631 360 2222	Telephone: (852) 26100 611	Telephone: (44) 161 622 4444
Fax: (49) 89 45 49 49 49	Fax: (1) 631 360 8222	Fax: (852) 24250 494	Fax: (44) 161 622 4446
europe.sales@zetex.com	usa.sales@zetex.com	asia.sales@zetex.com	hq@zetex.com

© 2007 Published by Zetex Semiconductors plc

Issue 1 - October 2007

© Zetex Semiconductors plc 2007